

Title (en)

Semiconductor device with two insulators of different dielectric constant and fabrication process thereof

Title (de)

Halbleiterelement mit zwei Isolatoren unterschiedlicher Dielektrizitätskonstante und Verfahren zu seiner Herstellung

Title (fr)

Dispositif semiconducteur avec deux isolants de constante diélectrique différentes et son procédé de fabrication

Publication

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Application

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Priority

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Abstract (en)

[origin: EP0851471A2] Described in the present invention is a semiconductor device in which a plurality of interconnect lines are disposed, through an insulating layer, on the same layer above a semiconductor substrate having a semiconductor element; a first interlevel insulator is formed selectively in a narrowly-spaced region between adjacent interconnect lines; a second interlevel insulator is formed in a widely-spaced region between said adjacent interconnect lines, and the first interlevel insulator has a smaller dielectric constant than the second interlevel insulator. According to such a constitution, strength and reliability can be heightened and performance can be improved easily even in a miniaturized interconnect structure. <IMAGE>

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IPC 8 full level

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Citation (search report)

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